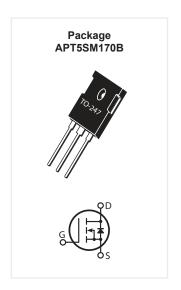


## PRELIMINARY 1700V, 5A, 0.95Ω

## Silicon Carbide N-Channel Power MOSFET

### DESCRIPTION

Silicon carbide (SiC) power MOSFET product line from Microsemi increase your performance over silicon MOSFET and silicon IGBT solutions while lowering your total cost of ownership for high-voltage applications.



### FEATURES / TYPICAL APPLICATIONS

#### **SiC MOSFET Features:**

- · Low capacitances and low gate charge
- Fast switching speed due to low internal gate resistance (ESR)
- Stable operation at high junction temperature, Tj(max) = +175C
- · Fast and reliable body diode

#### SiC MOSFET Benefits:

- High efficiency to enable lighter/compact system
- · Simple to drive and easy to parallel
- Improved thermal capabilities and lower switching losses
- Eliminates the need of external Free Wheeling Diode
- · Lower system cost of ownership

### Applications:

- PV inverter, converter and industrial motor drives
- · Smart grid transmission & distribution
- · Induction heating, and welding
- · H/EV powertrain and EV charger
- · Power supply and distribution

### **MAXIMUM RATINGS**

Symbol	Parameter	Ratings	Unit
V <sub>DSS</sub>	Drain Source Voltage	1700	V
	Continuous Drain Current @ T <sub>c</sub> = 25°C	5	
' <sub>D</sub>	Continuous Drain Current @ T <sub>c</sub> = 100°C	3.5	А
I <sub>DM</sub>	Pulsed Drain Current <sup>①</sup>	8	
$V_{GS}$	Gate-Source Voltage	-10 to +25	V
P <sub>D</sub>	Total Power Dissipation @ T <sub>c</sub> = 25°C	65	W
	Linear Derating Factor	0.43	W/°C

### THERMAL AND MECHANICAL CHARACTERISTICS

Symbol	Characteristic	Min	Тур	Max	Unit
$R_{\theta JC}$	Junction to Case Thermal Resistance		1.7	2.3	°C/W
T <sub>i</sub>	Operating Junction Temperature	-55		175	
T <sub>stg</sub>	Storage Junction Temperature Range	-55		150	°C
T <sub>L</sub>	Soldering Temperature for 10 Seconds (1.6mm from case)			260	
Torque	Mounting Torque (TO-247 Package), 6-32 or M3 screw			10	in·lbf
				1.1	N·m

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## STATIC CHARACTERISTICS

Symbol	Parameter	Test Conditions		Min	Тур	Max	Unit
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_{D} = 100\mu A$		1700			V
R <sub>DS(on)</sub>	Drain-Source On Resistance②	$V_{GS} = 20V, I_{D} = 2.5A$			950	1250	mΩ
V <sub>GS(th)</sub>	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 0.5 \text{mA}$		1.8	3.2		V
$\Delta V_{GS(th)}/\Delta T_{J}$	Threshold Voltage Temperature Coefficient				-7.6		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 1700V	T <sub>J</sub> = 25°C			100	
		$V_{GS} = 0V$	T <sub>J</sub> = 150°C			250	μA
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> = +20V / -10V				±100	nA

T<sub>J</sub> = 25°C unless otherwise specified

## **DYNAMIC CHARACTERISTICS**

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
C <sub>iss</sub>	Input Capacitance	V 0V/V 4000V		249		
C <sub>rss</sub>	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{GS} = 1000V$		3		pF
C <sub>oss</sub>	Output Capacitance	f = 1MHz		15		]
Q <sub>q</sub>	Total Gate Charge	V <sub>GS</sub> = 0/20V		21		nC
$Q_gs$	Gate-Source Charge	V <sub>DS</sub> = 850V		5		
$Q_{gd}$	Gate-Drain Charge	I <sub>D</sub> = 2.5A		8		
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DS</sub> = 850V		4		ns
t,	Current Rise Time	$V_{\rm DS} = 0.00V$		2		
t <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> = 2.5A		7		
t,	Current Fall Time	$R_{_{\rm G}} = 2.5\Omega^{ \textcircled{3}}$		4		
E <sub>on2</sub>	Turn-On Switching Energy <sup>®</sup>	L = 115 µH T <sub>c</sub> = 25°C		82		1
E <sub>off</sub>	Turn-Off Switching Energy			37		μJ
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DS} = 850V$ $V_{GS} = 0/20V$		3		
t <sub>r</sub>	Current Rise Time			2		1
t <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> = 2.5A		8		ns
t <sub>f</sub>	Current Fall Time	$R_{\rm g} = 2.5 \Omega^{ \textcircled{3}}$		5		
E <sub>on2</sub>	Turn-On Switching Energy <sup>®</sup>	L = 115 μH		87		
E <sub>off</sub>	Turn-Off Switching Energy	T <sub>c</sub> = 150°C		39		μJ
ESR	Equivalent Series Resistance	f = 1MHz, 25mV, Drain Short		1.43		Ω

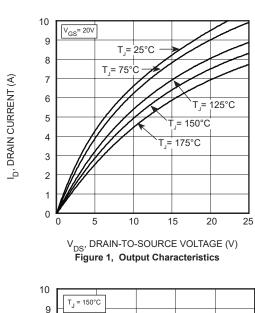
### **Source-Drain Diode Characteristics**

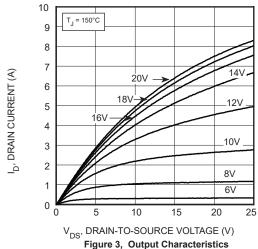
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V <sub>SD</sub>	Diode Forward Voltage	I <sub>SD</sub> = 2.5A, V <sub>GS</sub> = 0V		4		V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>SD</sub> = 2.5A, V <sub>DD</sub> = 850V dI/dt = -1000A/μs		14		ns
Q <sub>rr</sub>	Reverse Recovery Charge			24		nC
I <sub>rrm</sub>	Reverse Recovery Current			3.6		Α

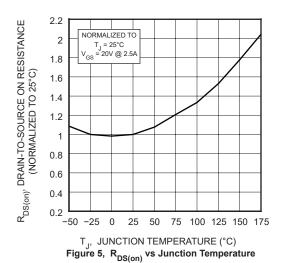
### T<sub>J</sub> = 25°C unless otherwise specified

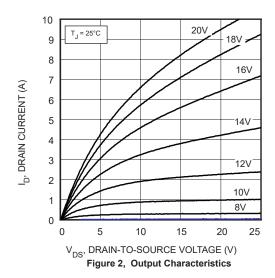
- ① Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature
- ② Pulse test: Pulse Width < 380µs, duty cycle < 2%.
- $\begin{tabular}{ll} \hline \end{tabular} \begin{tabular}{ll} \hline \end{t$
- $\bigoplus$  E<sub>on2</sub> includes energy of free wheeling diode.

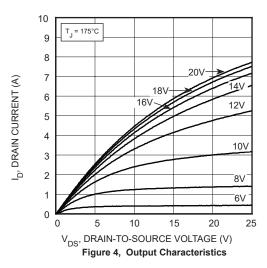


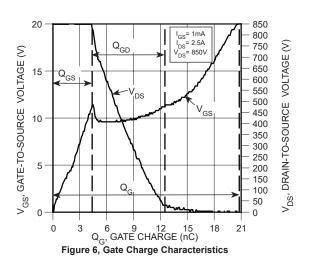


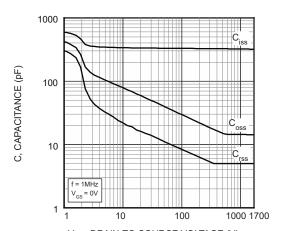




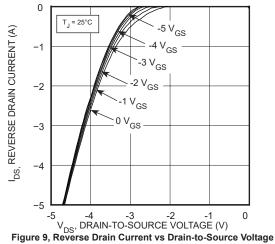




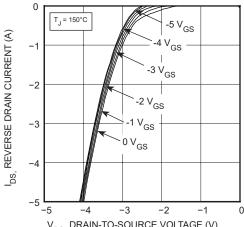




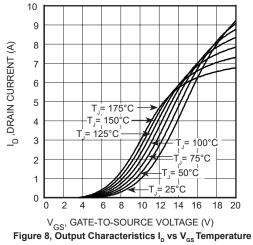
 $V_{DS}$ , DRAIN-TO-SOURCE VOLTAGE (V) Figure 7, Capacitance vs Drain-to-Source Voltage

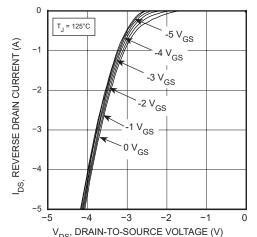


**Third Quadrant Conduction** 



 ${\rm V_{DS'}, DRAIN\text{-}TO\text{-}SOURCE\ VOLTAGE\ (V)}$  Figure 11, Reverse Drain Current vs Drain-to-Source Voltage **Third Quadrant Conduction** 





 ${\rm V_{DS}, DRAIN\text{-}TO\text{-}SOURCE\ VOLTAGE\ (V)}$  Figure 10, Reverse Drain Current vs Drain-to-Source Voltage **Third Quadrant Conduction** 

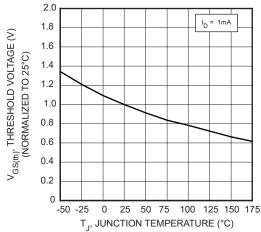
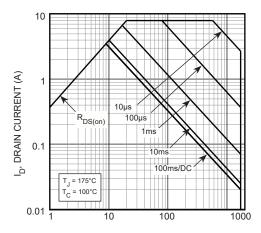


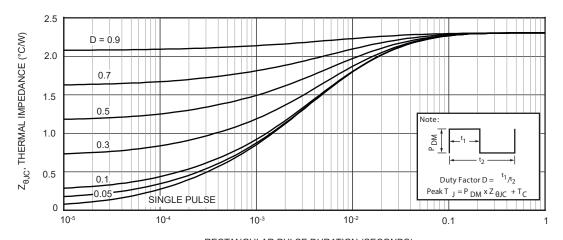
Figure 12, Threshold Voltage vs Temperature

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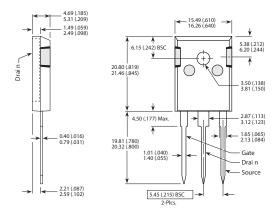


 $V_{\rm DS}$ , DRAIN-TO-SOURCE VOLTAGE (V) Figure 13, Forward Safe Operating Area



RECTANGULAR PULSE DURATION (SECONDS)
Figure 14, Maximum Effective Transient Thermal Impedance, Junction-To-Case vs Pulse Duration

### TO-247 (B) Package Outline



Dimensions in Millimeters (Inches)

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Power Matters."

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